



EVERYTHING

IN A

NEW

LIGHT.

Description

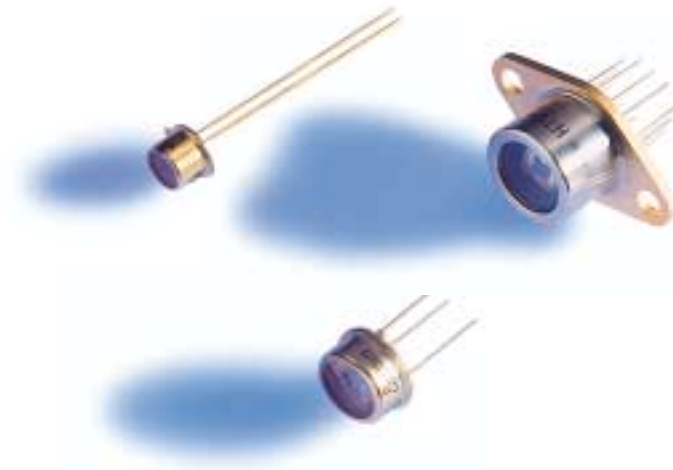
The PerkinElmer family of large-area InGaAs PIN photodiodes provide high responsivity from 800 nm to 1700 nm for applications including optical power meters, fiber optic test equipment, near-IR spectroscopy and instrumentation. All devices are planar passivated and feature low capacitance for extended bandwidth, and high shunt resistance for maximum sensitivity. Typical devices feature <1% non-linearity to optical powers $>+13$ dBm (20 mW), and uniformity within $\pm 2\%$ across the detector active area. Typical responsivity of 0.2 A/W at 850 nm for our large-area InGaAs devices allows use of a single detector in fiber optic test instrumentation designed to operate at 850, 1300, and 1550 nm.

Devices are available with active areas from 0.5 mm to 3.0 mm in TO-type packages or on thermoelectric coolers for increased sensitivity (see below). Photodiodes can also be mounted on customized ceramic sub-mounts to suit specific application requirements.

PerkinElmer Optoelectronics Canada is qualified to ISO-9001 and operates to MIL-Q-9858A and AQAP-1 quality standards. All devices undergo extended life-test and periodic process qualification programs to assure high reliability. In addition, all production devices are sourced from a qualified wafer, screened with a 16 hour, 200°C burn-in at -10V bias (C30619 and C30641) or -5V (C30642 and C30665), and tested to meet responsivity, spectral noise, capacitance, shunt resistance and dark current specifications.

Large-Area InGaAs Photodiodes

C30619, C30641, C30642, C30665



Features

- 0.5, 1.0, 2.0, and 3.0 mm diameters
- High responsivity from 850 nm to 1550 nm
- High shunt resistance, low dark current
- TE-cooled package options
- Low capacitance for fast response times

Applications

- Power meters
- Fiber identifiers
- Laser burn-in racks
- Near infrared instrumentation
- F.T.I.R. spectroscopy

Package Options

TE-Cooled Devices: Large-area detectors are available mounted on a 1-stage or 2-stage thermoelectric (TE) cooler. Cooling increases shunt resistance (see Figure 2) thereby reducing noise for increased sensitivity. Typical detector temperature is -10°C with a 1-stage TE cooler or -35°C using a 2-stage cooler. A TE-cooler option can be specified by adding the extension -TC (1-stage cooler) or -DTC (2-stage cooler) to the standard part number (see ordering guide). More information is available from the "TC-Series Cooled Photodiodes" datasheet from PerkinElmer Optoelectronics Canada.

Detector and Pre-Amplifier: Large-area InGaAs detectors are also available integrated with a preamplifier and TE-cooler. The HTE-series features large-area InGaAs detectors with a high gain hybrid transimpedance amplifier mounted on a 2-stage TE cooler. TE-cooling maximizes sensitivity and stabilizes op-amp offset and output characteristics. This provides an easy-to-use high sensitivity detector platform optimized for good temperature stability over a wide operating temperature range. More information is available from the HTE-series datasheet. The standard HTE-2642 incorporates a C30642E chip.

Specifications (at $V_R = V_{OP}$ (typical), 22°C)

| Parameter | C30619 | | | C30641 | | | Units |
|--|--------|---------|------|--------|---------|------|------------------------|
| | Min | Typ | Max | Min | Typ | Max | |
| Active Diameter | | 0.5 | | | 1.0 | | mm |
| Responsivity At 850 nm | 0.10 | 0.20 | | 0.10 | 0.20 | | A/W |
| At 1300 nm | 0.80 | 0.90 | | 0.80 | 0.90 | | A/W |
| At 1550 nm | 0.85 | 0.95 | | 0.85 | 0.95 | | A/W |
| Shunt Resistance ($V_R = 10\text{ mV}$) ¹ | 10 | 250 | | 5 | 50 | | M Ω |
| Dark Current | | 1 | 20 | | 5 | 50 | nA |
| Spectral Noise Current (10 kHz, 1.0 Hz) | | 0.02 | 0.10 | | 0.04 | 0.15 | pA/ $\sqrt{\text{Hz}}$ |
| Capacitance At $V_R = 0\text{V}$ | | 20 | 25 | | 100 | 125 | pF |
| At $V_R = V_{OP}$ | | 8 | 10 | | 40 | 50 | pF |
| Bandwidth (-3 dB, $R_L = 50\Omega$) | | 350 | | | 75 | | MHz |
| Linearity ² | | > +13 | | | > +13 | | dBm |
| Available package types | | D2, D14 | | | D2, D14 | | - |

Operating Ratings

| Parameter | C30619 | | | C30641 | | | Units |
|-------------------------|--------|-----|-----|--------|-----|-----|--------------------|
| | Min | Typ | Max | Min | Typ | Max | |
| Operating Voltage | 0 | 5 | 10 | 0 | 2 | 5 | V |
| Breakdown Voltage | 20 | 80 | | 20 | 80 | | V |
| Maximum Forward Current | | | 10 | | | 10 | mA |
| Maximum Photocurrent | | | 100 | | | 100 | mA |
| Power Dissipation | | | 100 | | | 100 | mW |
| Storage Temperature | -60 | | 125 | -80 | | 125 | $^{\circ}\text{C}$ |
| Operating Temperature | -40 | | 85 | -40 | | 85 | $^{\circ}\text{C}$ |

Note 1. Selected higher shunt resistance devices are available to special order.

Note 2. Maximum optical power level for $\pm 0.04\text{ dB}$ ($\pm 1\%$) responsivity variation under 1300 nm CW illumination, at $V_R = V_{OP}$ (typ).

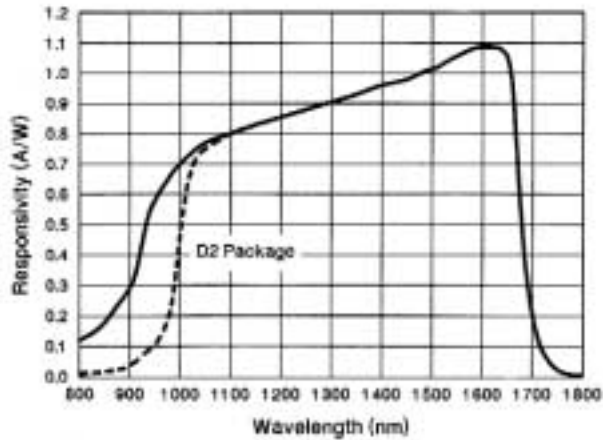


Figure 1. Typical Responsivity vs. Wavelength.

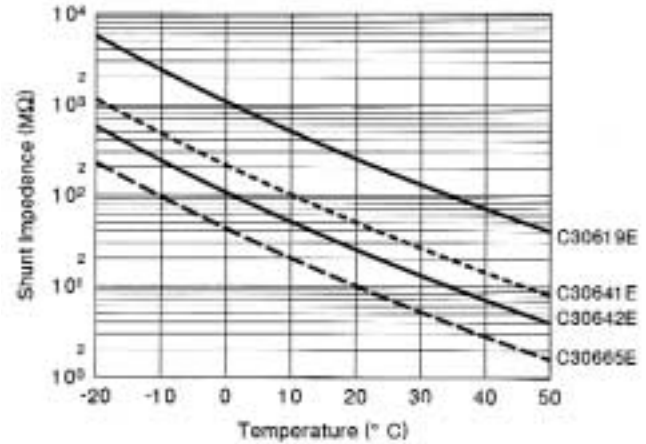


Figure 2. Typical Shunt Resistance as a Function of Temperature.

Specifications (at $V_R = V_{OP}$ (typical), 22°C)

| Parameter | C30642 | | | C30665 | | | Units |
|--|--------|-----------------|------|--------|-----------------|------|--------|
| | Min | Typ | Max | Min | Typ | Max | |
| Active Diameter | | 2.0 | | | 3.0 | | mm |
| Responsivity At 850 nm | 0.10 | 0.20 | | 0.10 | 0.20 | | A/W |
| At 1300 nm | 0.80 | 0.90 | | 0.80 | 0.90 | | A/W |
| At 1550 nm | 0.85 | 0.95 | | 0.85 | 0.95 | | A/W |
| Shunt Resistance ($V_R = 10$ mV) ¹ | 2 | 25 | | 1 | 10 | | MΩ |
| Dark Current | | 10 ³ | | | 25 ³ | | nA |
| Spectral Noise Current (10 kHz, 1.0 Hz) | | 0.03 | 0.15 | | 0.04 | 0.20 | pA/√Hz |
| Capacitance At $V_R = 0$ V | | 300 | 500 | | 1000 | 1250 | pF |
| At $V_R = 2.0$ V (typical) | | 150 | | | 400 | | pF |
| Bandwidth (-3 dB, $R_L = 50$ Ω) | | 20 | | | 3.0 | | MHz |
| Linearity ² | | +11 | | | +11 | | dBm |
| Available package types | | D15 | | | D15 | | - |

Operating Ratings

| Parameter | C30642 | | | C30665 | | | Units |
|-------------------------|--------|-----|-----|--------|-----|-----|-------|
| | Min | Typ | Max | Min | Typ | Max | |
| Operating Voltage | | 0 | 5 | | 0 | 5 | V |
| Breakdown Voltage | 15 | 50 | | 10 | 50 | | V |
| Maximum Forward Current | | | 10 | | | 10 | mA |
| Maximum Photocurrent | | | 100 | | | 100 | mA |
| Power Dissipation | | | 250 | | | 250 | mW |
| Storage Temperature | -60 | | 125 | -80 | | 125 | °C |
| Operating Temperature | -40 | | 85 | -40 | | 85 | °C |

Note 1. Selected higher shunt resistance devices are available to special order.

Note 2. Maximum optical power level for ± 0.04 dB ($\pm 1\%$) responsivity variation under 1300 nm CW illumination, at $V_R = V_{OP}$ (typ).

Note 3. At $V_R = 2.0$ V

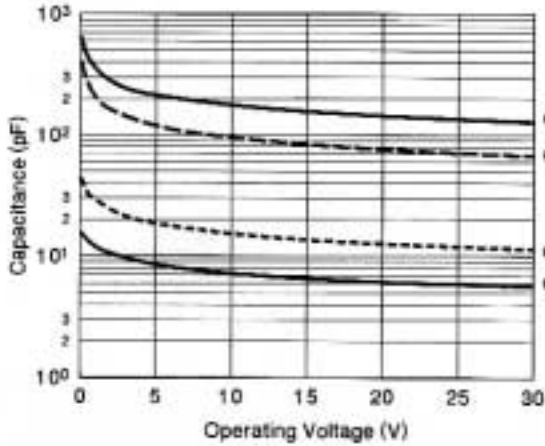


Figure 3. Typical Capacitance vs. Operating Voltage.

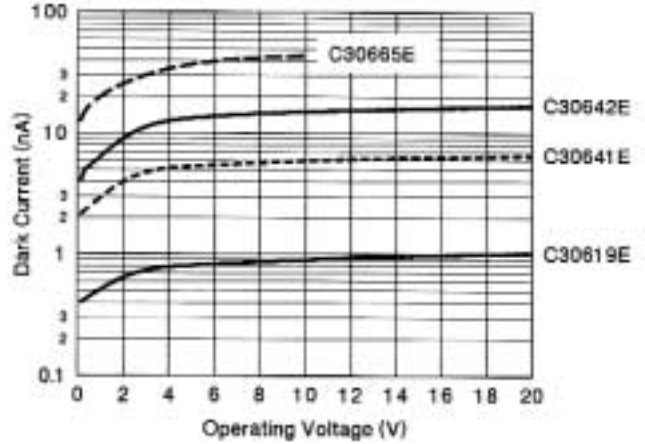


Figure 4. Typical Dark Current vs. Operating Voltage.

| Wavelength (nm) | Temperature Coefficient ¹ (%/°C) |
|-----------------|---|
| 850 | -0.121 |
| 1060 | 0.039 |
| 1300 | 0.012 |
| 1550 | 0.009 |
| 1650 | 0.085 (20°C to 85°C) |
| | 1.287 (-40°C to 20°C) |

Note1: Measured from -40°C to +85°C except 1650nm, as indicated.

Figure 5. Typical Responsivity Temperature Coefficients.

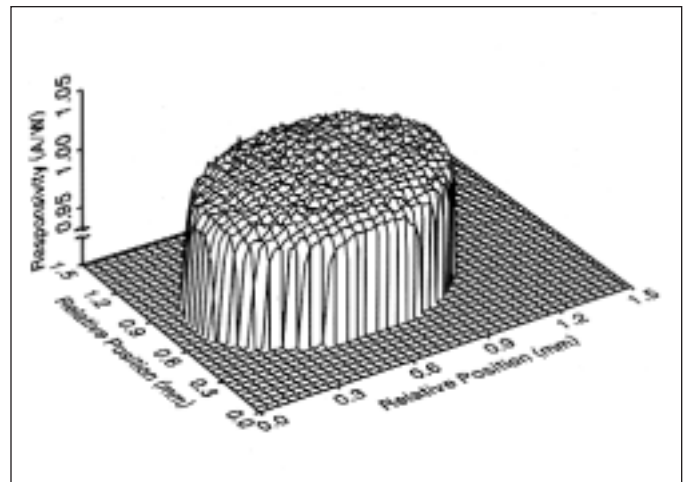


Figure 6. Typical Responsivity Scan of a 1mm Photodiode.

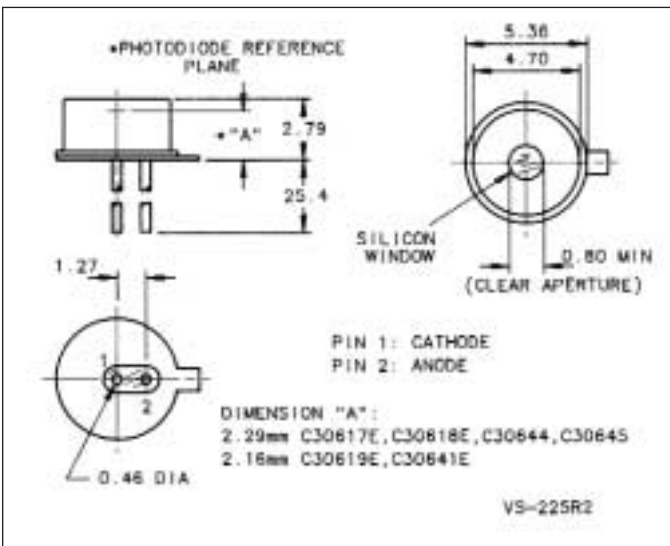


Figure 7. Package D2: TO-18 Low Profile with Silicon Window. To special order.

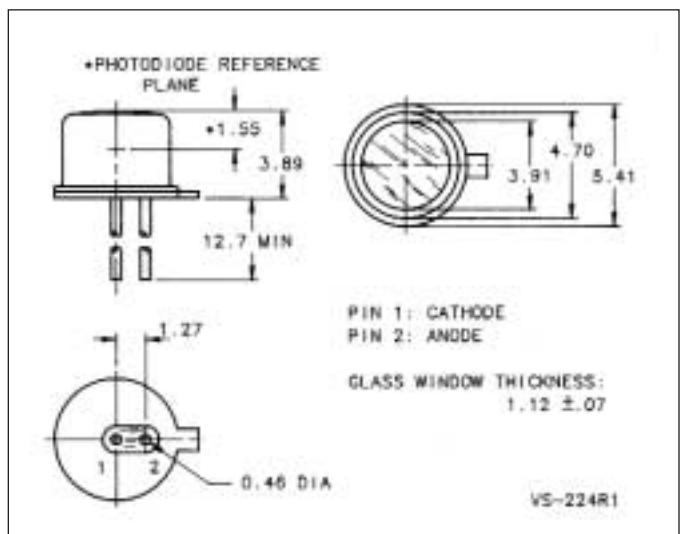


Figure 8. Package D-14: TO-18 with Glass Window.

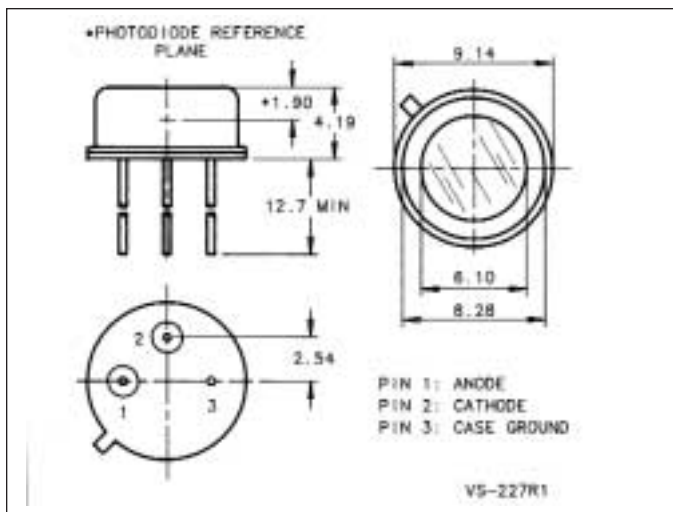
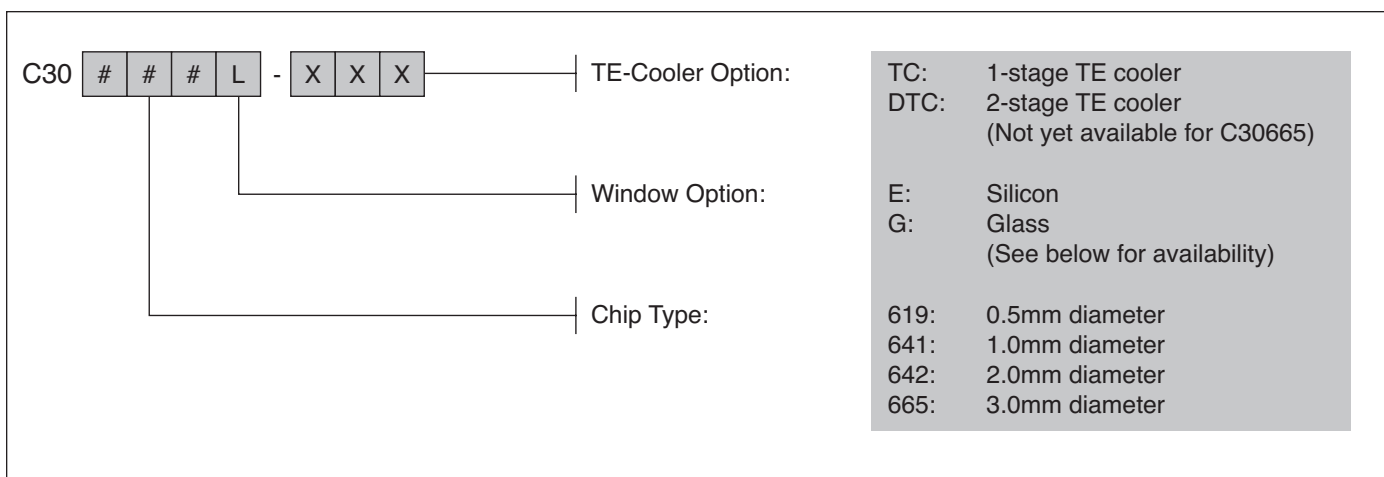


Figure 9. Package D15: TO-5 with Glass Window.

Ordering Guide



Device Package Availability

| Window Option | Window Type | Package Type | | | |
|---------------|-------------|-----------------|-----------------|--------|--------|
| | | C30619 | C30641 | C30642 | C30665 |
| E | Silicon | D2 ¹ | D2 ¹ | - | - |
| G | Glass | D14 | D14 | D15 | D15 |

Note 1: Special Order